

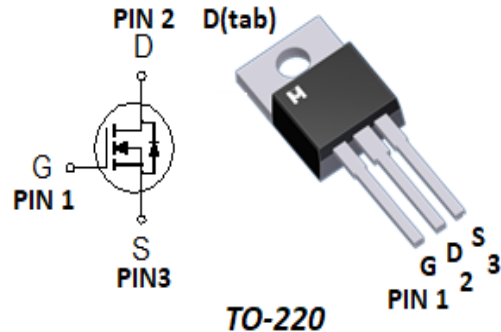
N-Channel Logic Level Enhancement Mode Field Effect Transistor

Product Summary:

BV_{DSS}	60V
$R_{DS(on)}$ (MAX.)	8m Ω
I_D	110A

UIS, Rg 100% Tested

RoHS & Halogen Free & TSCA Compliant



ABSOLUTE MAXIMUM RATINGS ($T_A = 25\text{ }^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNIT
Gate-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current	$T_C = 25\text{ }^\circ\text{C}$	I_D	110	A
	$T_C = 100\text{ }^\circ\text{C}$		80	
Pulsed Drain Current ¹		I_{DM}	380	
Avalanche Current		I_{AS}	60	
Avalanche Energy	$L = 0.1\text{mH}$, $I_{AS}=60\text{A}$, $R_G=25\Omega$	E_{AS}	180	mJ
Repetitive Avalanche Energy ²	$L = 0.05\text{mH}$	E_{AR}	90	
Power Dissipation	$T_C = 25\text{ }^\circ\text{C}$	P_D	166	W
	$T_C = 100\text{ }^\circ\text{C}$		68	
Operating Junction & Storage Temperature Range		T_j, T_{stg}	-55 to 150	$^\circ\text{C}$

100% UIS testing in condition of $V_D=30\text{V}$, $L=0.1\text{mH}$, $V_G=10\text{V}$, $I_L=40\text{A}$, Rated $V_{DS}=60\text{V}$ N-CH

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case	$R_{\theta JC}$		0.75	$^\circ\text{C} / \text{W}$
Junction-to-Ambient	$R_{\theta JA}$		62.5	

¹Pulse width limited by maximum junction temperature.

²Duty cycle $\leq 1\%$

³The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25\text{ }^\circ\text{C}$.



ELECTRICAL CHARACTERISTICS (T_J = 25 °C, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} = 0V, I _D = 250μA	60			V
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250μA	2	3	4	
Gate-Body Leakage	I _{GSS}	V _{DS} = 0V, V _{GS} = ±20V			±100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 48V, V _{GS} = 0V			1	μA
		V _{DS} = 40V, V _{GS} = 0V, T _J = 125 °C			25	
On-State Drain Current ¹	I _{D(ON)}	V _{DS} = 10V, V _{GS} = 10V	110			A
Drain-Source On-State Resistance ¹	R _{DS(ON)}	V _{GS} = 10V, I _D = 20A		6.6	8.0	mΩ
Forward Transconductance ¹	g _{fs}	V _{DS} = 5V, I _D = 20A		50		S
DYNAMIC						
Input Capacitance	C _{iss}	V _{GS} = 0V, V _{DS} = 25V, f = 1MHz		2675		pF
Output Capacitance	C _{oss}			345		
Reverse Transfer Capacitance	C _{rss}			120		
Gate Resistance	R _g	V _{GS} = 15mV, V _{DS} = 0V, f = 1MHz		1.9		Ω
Total Gate Charge ^{1,2}	Q _g	V _{DS} = 30V, V _{GS} = 10V, I _D = 20A		35		nC
Gate-Source Charge ^{1,2}	Q _{gs}			12		
Gate-Drain Charge ^{1,2}	Q _{gd}			11		
Turn-On Delay Time ^{1,2}	t _{d(on)}	V _{DS} = 30V, I _D = 1A, V _{GS} = 10V, R _{GS} = 6Ω		15		nS
Rise Time ^{1,2}	t _r			70		
Turn-Off Delay Time ^{1,2}	t _{d(off)}			100		
Fall Time ^{1,2}	t _f			80		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (T_C = 25 °C)						
Continuous Current	I _S				110	A
Pulsed Current ³	I _{SM}				380	
Forward Voltage ¹	V _{SD}	I _F = 20A, V _{GS} = 0V			1.3	V
Reverse Recovery Time	t _{rr}	I _F = 25A, dI _F /dt = 100A / μS		30		nS
Reverse Recovery Charge	Q _{rr}			150		nC

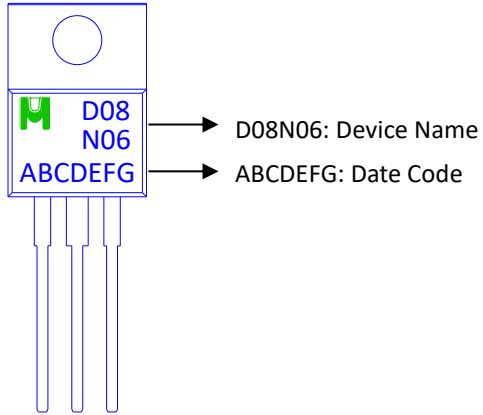
¹Pulse test : Pulse Width ≤ 300 μsec, Duty Cycle ≤ 2%.

²Independent of operating temperature.

³Pulse width limited by maximum junction temperature.

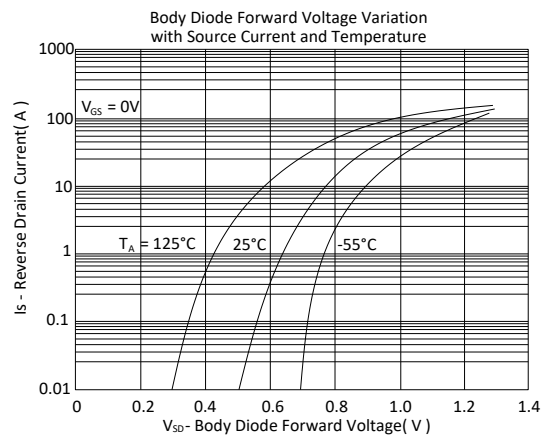
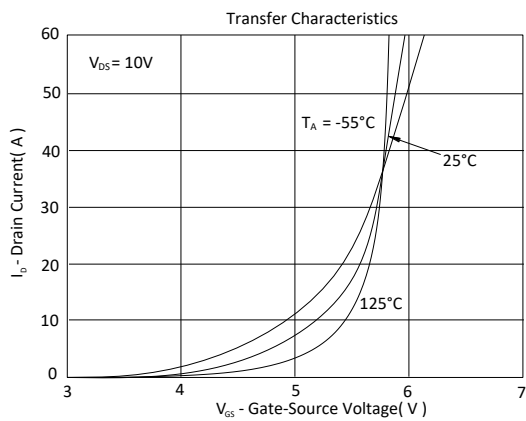
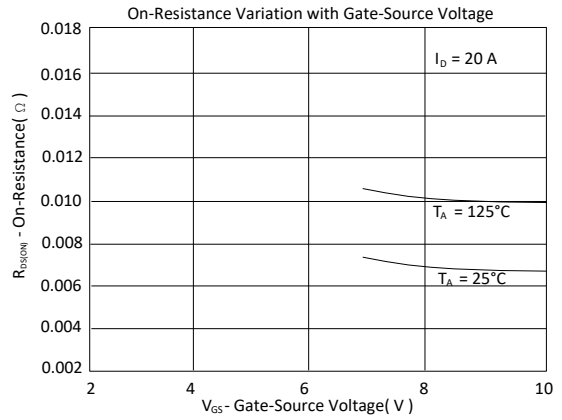
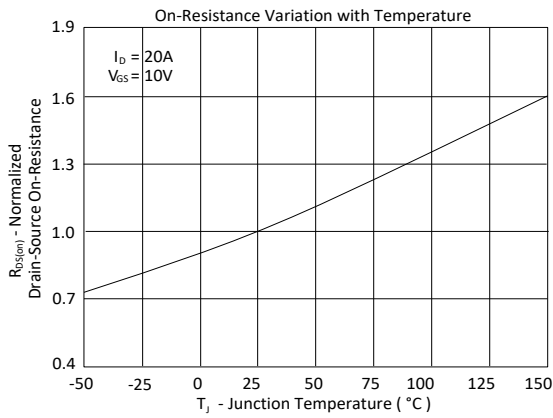
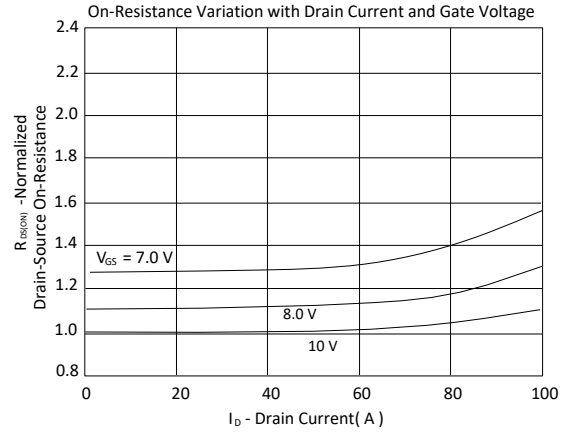
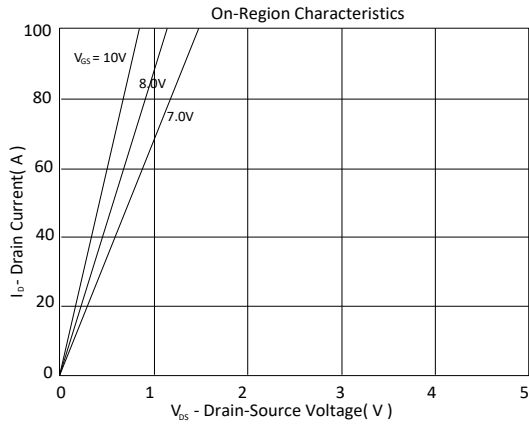
Ordering & Marking Information:

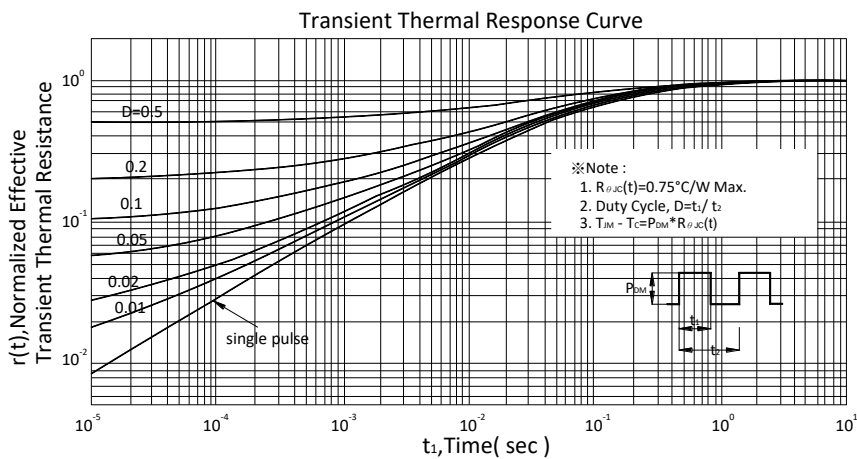
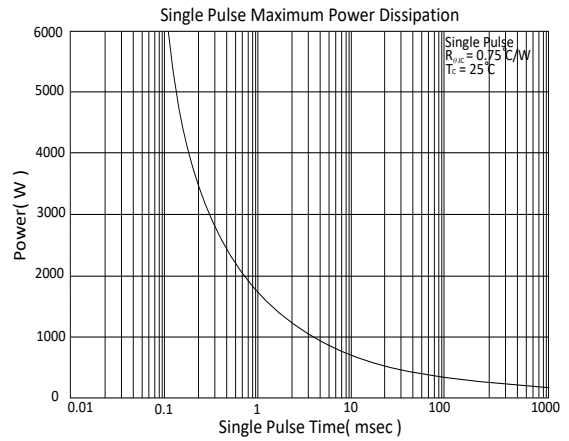
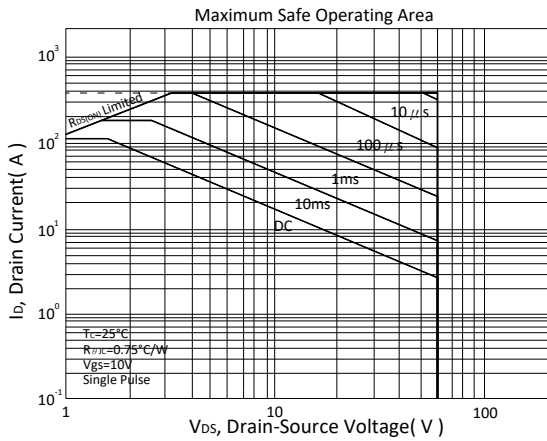
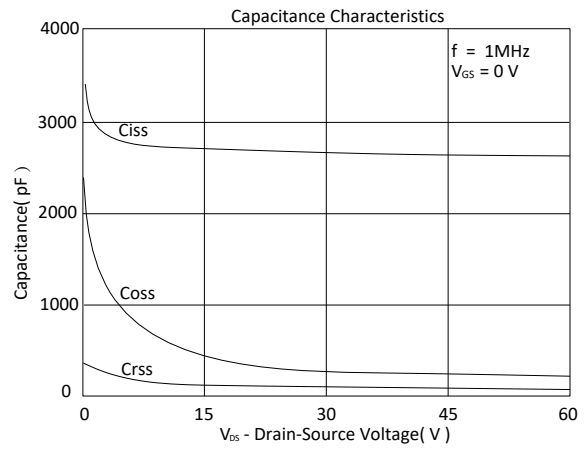
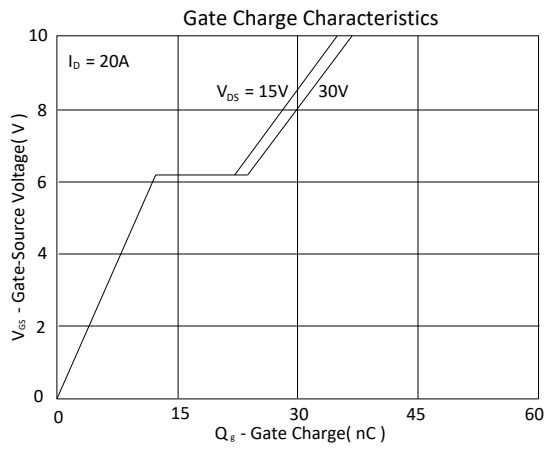
Device Name: EMD08N06E for TO-220





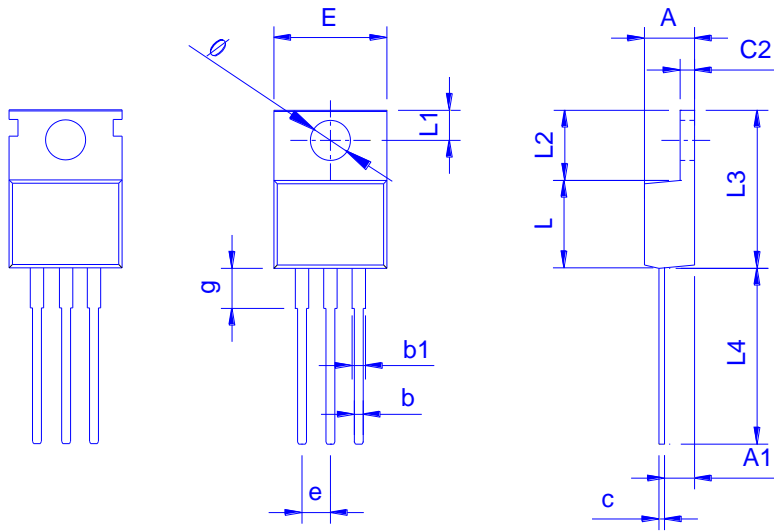
TYPICAL CHARACTERISTICS







Outline Drawing



Dimension in mm

Dimension	A	A1	b	b1	c	c2	E	L	L1	L2	L3	L4	Ø	e	g
Min.	4.240	2.250	0.700	1.170	0.310	1.150	9.910	8.500	2.590	6.100	14.700	12.700	3.400	2.440	2.850
Typ.	4.440	2.400	0.800	1.550	0.500	1.270	10.160	8.920	2.800	6.300	15.370	13.720	3.840	2.540	3.800
Max.	4.700	2.820	0.910	1.750	0.650	1.400	10.360	9.750	3.250	6.800	16.900	13.970	3.935	2.640	4.000



◆ Tube Information: 50pcs/Tube (1000pcs/Box)

